

N-channel Enhancement Mode Power MOSFET

TOLL/NMOS/150V/ \pm 20V/3.3V/263A/3.5m Ω

Rev_{0.1}





150V, 3.5mΩ, 263A, N-channel MOSFET

1.Features

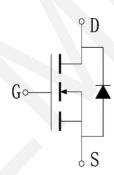
- ◆ Excellent RDS(ON) and Low Gate Charge
- ◆ 100% UIS Tested
- 100% ΔVds Tested
- ◆ 100% RG Tested
- Halogen-free; RoHS-compliant

2.Applications

- ◆ Load Switch
- PWM Application
- Power Management







Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Package	Marking	PCS/Reel	PCS/CTN.
WX035N15LL	TOLL	035N15	2,000	16,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter		Symbol	Maximum	Units	
Drain to Source Voltage		V_{DSS}	150	٧	
Gate to Source Voltage		V _{GSS}	±20	V	
Drain Current (DC)	T C = 25°C	I _D	263	А	
	T C = 100°C	I _D	166	А	
Drain Current (Pulse), PW≤300μs		I _{DM}	1052	А	
Avalanche Energy, Single Pulsed		E _{AS}	1350	mJ	
Total Dissipation	T C = 25°C	P_{D}	625	W	
	T C = 100°C	P_{D}	250	W	
Junction Temperature		T_{j}	150	°C	
Storage Temperature		T_{stg}	-55 to +150	°C	

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Junction to Ambient	$R_{ hetaJA}$	40	°C/W
Junction to case	$R_{ heta JC}$	0.2	°C/W

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

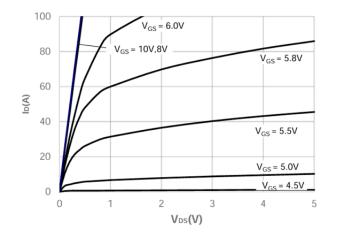
6.Electrical Characteristics at Ta=25°C (Note 2)

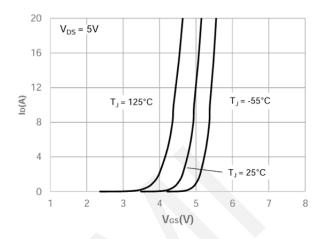
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	150	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} =150V, V _{GS} = 0V	-	-	1	μA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =250μA	2.5	3.3	4.2	V
Static Drain to Source On-State Resistance	R _{DS(on)}	I _D = 20A, V _{GS} = 10V	-	3.5	4.2	mΩ
Input Capacitance	C_{iss}	V _{GS} =0V,	-	8622	-	nF
Output Capacitance	C _{oss}	V _{DS} =75V,	-	772	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	-	26	-	pF
Turn-on Delay Time	t _{d(on)}		-	32	-	ns
Rise Time	t _r	$V_{DS} = 75V, I_{D}=20A,$	-	60	-	ns
Turn-off Delay Time	$t_{d(off)}$	$V_{GS} = 10V,$ $R_{GEN} = 3\Omega$	-	87	-	ns
Fall Time	t _f	SEN -	-	48	-	ns
	Qg	$V_{DS} = 75V,$ $V_{GS} = 0 \text{ to } 10V,$ $I_{D} = 20A$	-	125	-	nC
Total Gate Charge	Q_{gs}		-	46	-	nC
	Q_{gd}		-	32	-	nC
Diode Forward Voltage	V_{FSD}	I _S =20A, V _{GS} = 0	0.5	-	1.2	V

Note 2: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

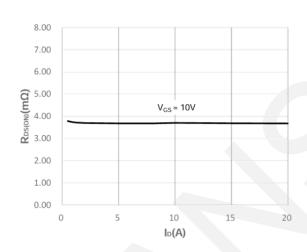


7. Typical electrical and thermal characteristics

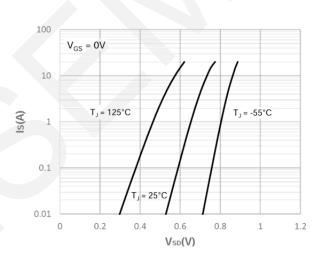




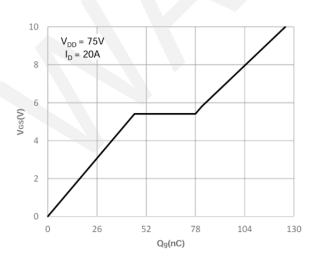
Saturation Characteristics



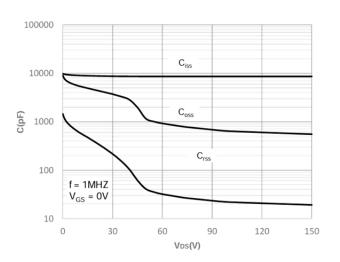
Transfer Characteristics



R_{DS(on)}vs.Drain Current



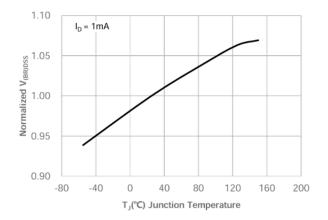
Body-Diode Characteristics

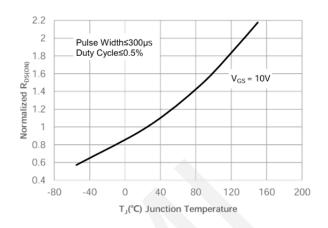


Gate Charge Characteristics

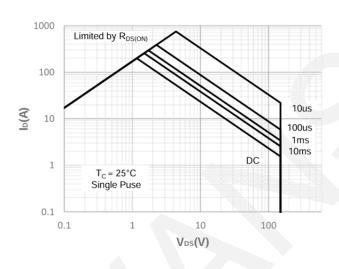
Capacitance Characteristics



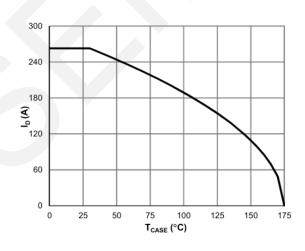




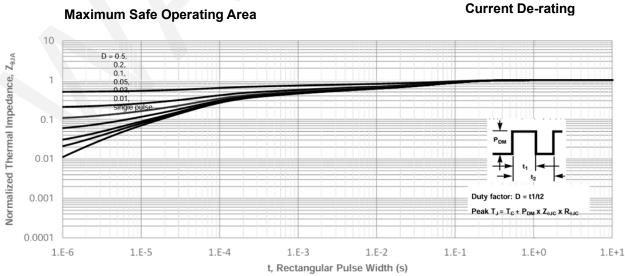
Normalized Breakdown voltage vs. **Junction Temperature**



Normalized on Resistance vs. **Junction Temperature**



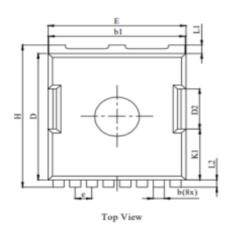
Maximum Safe Operating Area

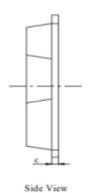


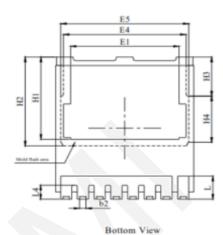
Normalized Maximum Transient Thermal Impedance

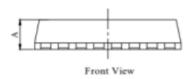


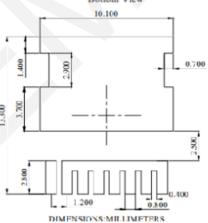
8.Package Dimensions











DIM	MILLIMETER			
DIM.	MIN	NOM	MAX	
Α	2.20	2.30	2.50	
b	0.70	0.80	0.90	
bl	9.70	9.80	9.90	
b2	0.42	0.46	0.50	
С	0.40	0.50	0.65	
D	10.28	10.38	10.58	
D2	3.30			
E	9.70	9.90	10.10	
E1	7.80			
E4	8.80			
E5	9.20			
e	1.20(BSC)			
Н	11.48	11.68 11.88		
HI	6.55	6.75	6.85	
H2	7.30			
H3	3.20			
H4	3.80			
K1	4.18			
L	1.70	1.90	2.10	
L1	0.70			
L2	0.60			
L4	1.00	1.15	1.30	



9. Important Notice

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